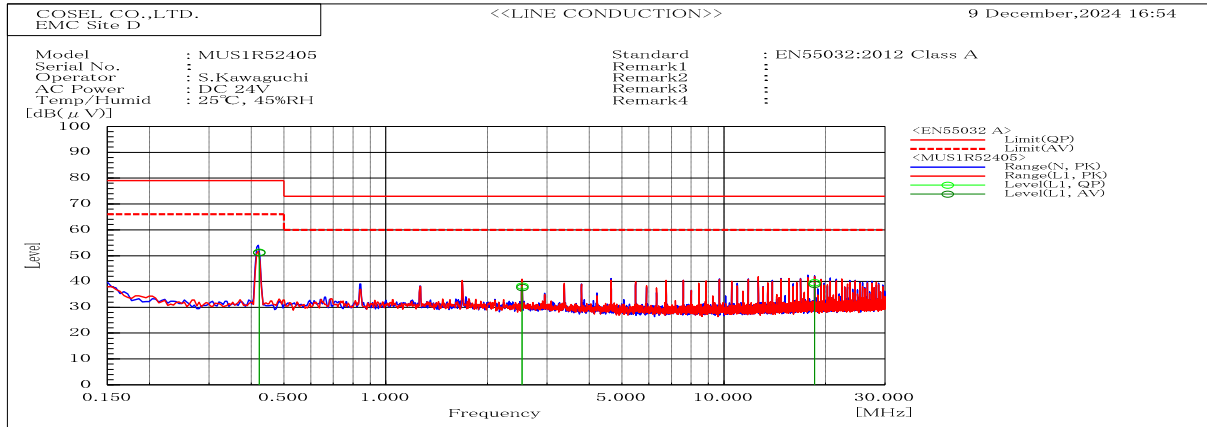
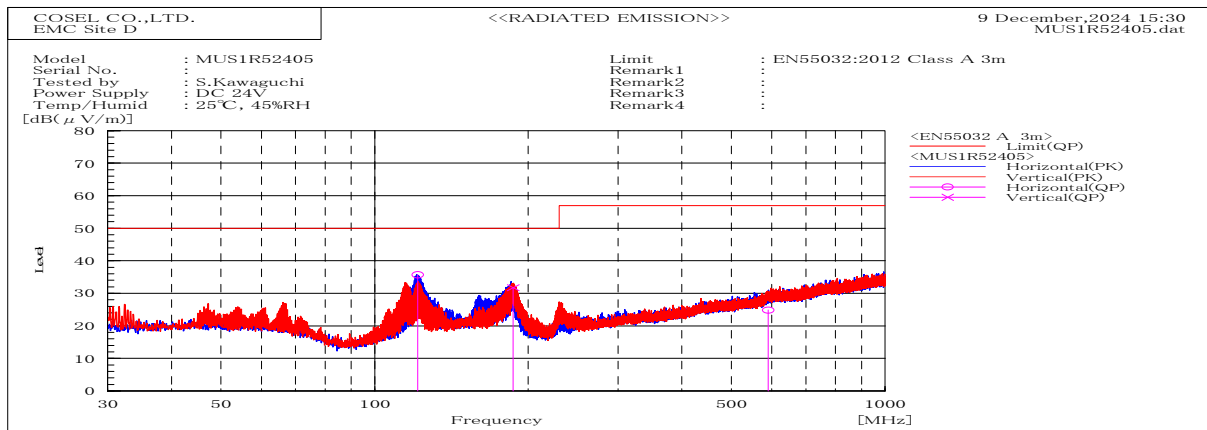


DATA SHEET		Date	05-Mar-25
Model	MUS1R52405	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	S.Kawaguchi



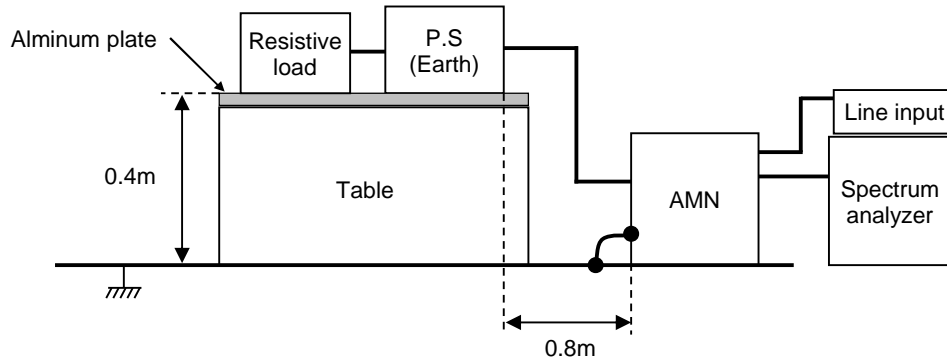
Frequency	Line	Level		Limit		Margin		Pass/Fail	Remark
MHz		dB(μV)		dB(μV)		dB			
		QP	AV	QP	AV	QP	AV		
0.422	L1	51.3	51.1	79	66	27.7	14.9	Pass	
2.531	L1	38.3	37.7	73	60	34.7	22.3	Pass	
18.564	L1	39.5	38.9	73	60	33.5	21.1	Pass	



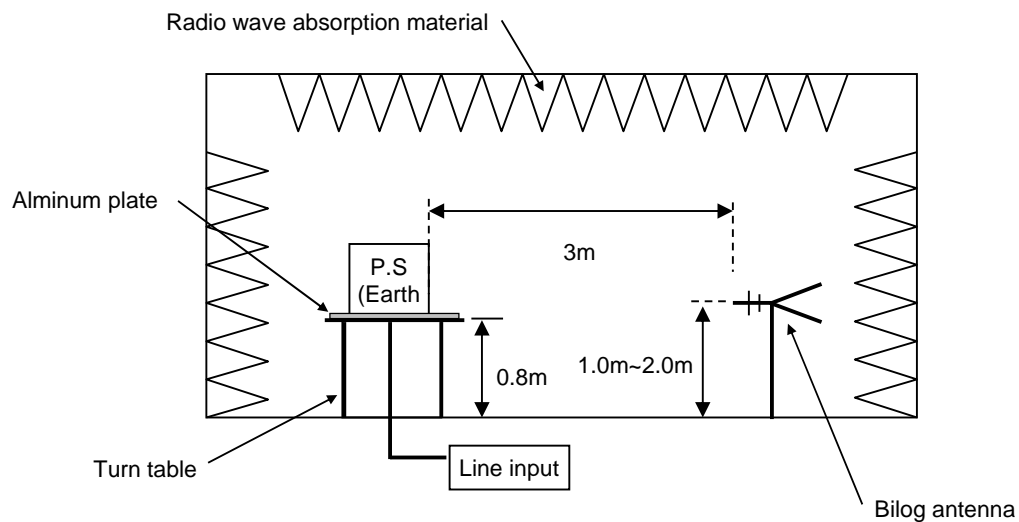
Frequency	Polarization	Stability	Level	Limit	Margin	Pass/Fail	Height	Angle	Remark
MHz			dB(μV/m)	dB(μV/m)	dB				
			QP	QP	QP		cm	deg	
121.472	H	Stable	35.7	50	14.3	Pass	199.7	47.5	
186.847	V	Stable	31.7	50	18.3	Pass	100.2	25.8	
590.381	H	Stable	24.9	57	32.1	Pass	136.6	9.3	

DATA SHEET		Date	05-Mar-25
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	S.Kawaguchi

1. Line conduction



2. Radiated emission



Conditions

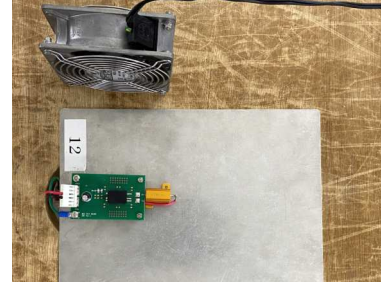
Test : EMI
Model Name: MUS1R5□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

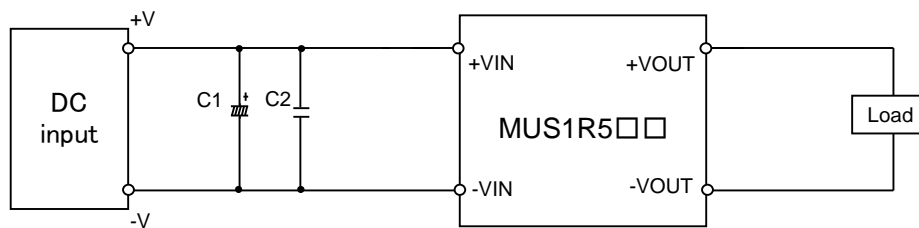


Fig.1 MUS1R505□, MUS1R512□, MUS1R524□ Testing circuitry

C1 :	MUS1R505□	16V 220 μ F	Electric capacitor (UPWseries NICHICON)
	MUS1R512□	50V 100 μ F	Electric capacitor (UPWseries NICHICON)
	MUS1R524□	-	
C2 :	MUS1R505□	16V 22 μ F	Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING)
	MUS1R512□	25V 22 μ F	Ceramic capacitor (C3216JB1E226MT TDK)
	MUS1R524□	50V 10 μ F	Ceramic capacitor (C3216X7R1H106KT TDK)

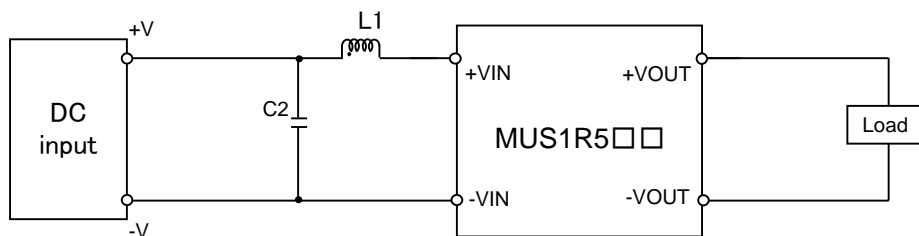


Fig.2 MUS1R548□ Testing circuitry

C2 :	MUS1R548□	100V 2.2 μ F	Ceramic capacitor (C3216X7S2A225KT TDK)
L1 :	MUS1R548□	520mA 15 μ H	Inductor (LQH32PN150MN0L MURATA MANUFACTURING)